捷多**那LV2322**β**打EV2322Y**小**TLV2324Y** LinCMOS™ LOW-VOLTAGE LOW-POWER OPERATIONAL AMPLIFIERS

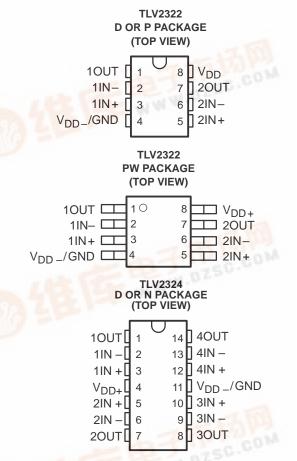
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- Wide Range of Supply Voltages Over Specified Temperature Range: $T_{\Delta} = -40^{\circ}\text{C to } 85^{\circ}\text{C} \dots 2 \text{ V to } 8 \text{ V}$
- Fully Characterized at 3 V and 5 V
- Single-Supply Operation
- Common-Mode Input Voltage Range Extends Below the Negative Rail and up to V_{DD} -1 V at T_A = 25°C
- Output Voltage Range Includes Negative
 Rail
- High Input Impedance . . . 10¹² Ω Typical
- ESD-Protection Circuitry
- Designed-In Latch-Up Immunity

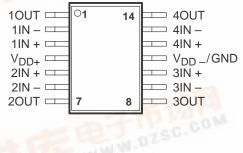
description

The TLV232x operational amplifiers are in a family of devices that has been specifically designed for use in low-voltage single-supply applications. This amplifier is especially well suited to ultra-low-power systems that require devices to consume the absolute minimum of supply currents. Each amplifier is fully functional down to a minimum supply voltage of 2 V, is fully characterized, tested, and specified at both 3-V and 5-V power supplies. The common-mode input voltage range includes the negative rail and extends to within 1 V of the positive rail.

These amplifiers are specifically targeted for use in very low-power, portable, battery-driven applications with the maximum supply current per operational amplifier specified at only 27 μ A over its full temperature range of -40° C to 85°C.



TLV2324 PW PACKAGE (TOP VIEW)



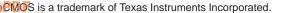
AVAILABLE OPTIONS

	V		PACKAGED	DEVICES		0.UD 50.048
TA	V _{IO} max AT 25°C	SMALL OUTLINE [†] (D)	PLASTIC DIP (N)	PLASTIC DIP (P)	TSSOP [‡] (PW)	CHIP FORM§ (Y)
-40°C to 85°C	9 mV	TLV2322ID	_	TLV2322IP	TLV2322IPWLE	TLV2322Y
-40 C 10 65°C	10 mV	TLV2324ID	TLV2324IN	_	TLV2324IPWLE	TLV2324Y

The D package is available taped and reeled. Add R suffix to the device type (e.g., TLV2322IDR).

§ Chip forms are tested at 25°C only.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





[‡]The PW package is only available left-end taped and reeled (e.g., TLV2322IPWLE).

description (continued)

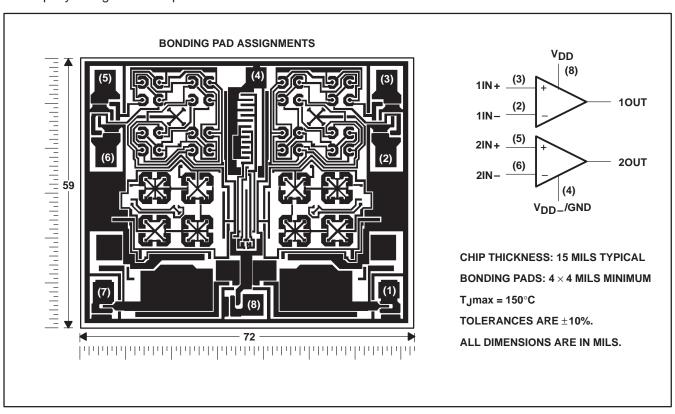
Low-voltage and low-power operation has been made possible by using the Texas Instruments silicon-gate LinCMOS technology. The LinCMOS process also features extremely high input impedance and ultra-low bias currents making these amplifiers ideal for interfacing to high-impedance sources such as sensor circuits or filter applications.

To facilitate the design of small portable equipment, the TLV232x is made available in a wide range of package options, including the small-outline and thin-shrink small-outline packages (TSSOP). The TSSOP package has significantly reduced dimensions compared to a standard surface-mount package. Its maximum height of only 1.1 mm makes it particularly attractive when space is critical.

The device inputs and outputs are designed to withstand –100-mA currents without sustaining latch-up. The TLV232x incorporates internal ESD-protection circuits that prevent functional failures at voltages up to 2000 V as tested under MIL-STD 883C, Method 3015.2; however, care should be exercised in handling these devices as exposure to ESD can result in the degradation of the device parametric performance.

TLV2322Y chip information

This chip, when properly assembled, displays characteristics similar to the TLV2322I. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.



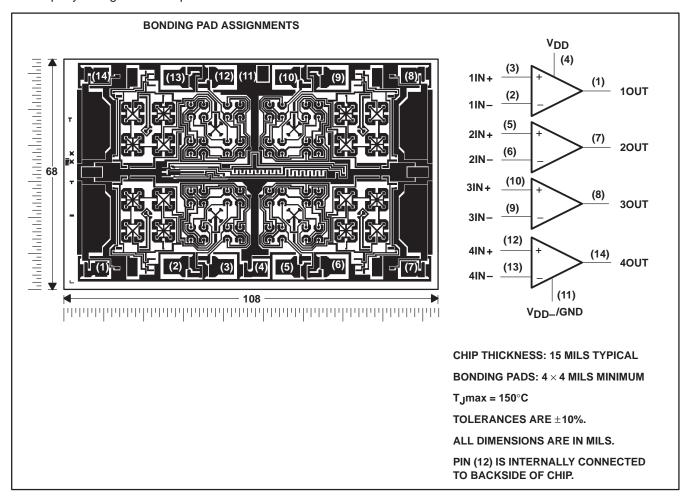


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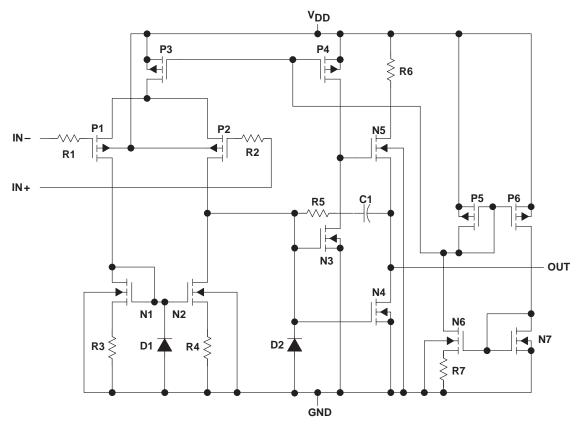
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TLV2324Y chip information

This chip, when properly assembled, display characteristics similar to the TLV2324. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.



equivalent schematic (each amplifier)



ACTUAL DEVI	CE COMPONEN	T COUNT†
COMPONENT	TLV2342	TLV2344
Transistors	54	108
Resistors	14	28
Diodes	4	8
Capacitors	2	4

 $[\]ensuremath{^{\dagger}}$ Includes both amplifiers and all ESD, bias, and trim circuitry.



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absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage, V _{DD} (see Note 1)	
Differential input voltage, V _{ID} (see Note 2)	
Input voltage range, V _I (any input)	
Input current, I ₁	±5 mA
Output current, I _O	±30 mA
Duration of short-circuit current at (or below) T _A = 25°C (see Note 3)	unlimited
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	–40°C to 85°C
Storage temperature range	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values, except differential voltages, are with respect to network ground.
 - 2. Differential voltages are at the noninverting input with respect to the inverting input.
 - 3. The output may be shorted to either supply. Temperature and/or supply voltages must be limited to ensure that the maximum dissipation rating is not exceeded (see application section).

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ} \mbox{\scriptsize C}$	DERATING FACTOR	T _A = 85°C
PACKAGE	POWER RATING	ABOVE $T_A = 25^{\circ}C$	POWER RATING
D-8	725 mW	5.8 mW/°C	377 mW
D-14	950 mW	7.6 mW/°C	494 mW
N	1575 mW	12.6 mW/°C	819 mW
Р	1000 mW	8.0 mW/°C	520 mW
PW-8	525 mW	4.2 mW/°C	273 mW
PW-14	700 mW	5.6 mW/°C	364 mW

recommended operating conditions

		MIN	MAX	UNIT
upply voltage, V _{DD}				V
Common-mode input voltage, V _{IC}	V _{DD} = 3 V	-0.2	1.8	
	V _{DD} = 5 V	-0.2	3.8	1 °
Operating free-air temperature, T _A		-40	85	°C



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TLV2322 electrical characteristics at specified free-air temperature

						TLV2	2322				
	PARAMETER	TEST CONDITIONS	T _A †	V	DD = 3 \	/	V	DD = 5 \	/	UNIT	
				MIN	TYP	MAX	MIN	TYP	MAX		
\/	Input offset voltage	V _O = 1 V, V _{IC} = 1 V,	25°C		1.1	9		1.1	9	mV	
VIO	input onset voltage	$R_S = 50 \Omega$, $R_L = 1 M\Omega$	Full range			11			11	IIIV	
ανιο	Average temperature coefficient of input offset voltage		25°C to 85°C		1			1.1		μV/°C	
lio	Input offset current (see Note 4)	V _O = 1 V,	25°C		0.1			0.1		рA	
110	input offset current (see Note 4)	V _{IC} = 1 V	85°C		22	1000		24	1000	PΛ	
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	25°C		0.6			0.6		pА	
.ID	mpar side editerit (eee trete 1)	V _{IC} = 1 V	85°C		175	2000		200	2000	Ρ, τ	
				-0.2	-0.3		-0.2	-0.3		.,	
			25°C	to 2	to 2.3		to 4	to 4.2		V	
VICR	Common-mode input voltage range (see Note 5)			-0.2			-0.2	7.2			
			Full range	-0.2 to			-0.2 to			V	
				1.8			3.8				
			25°C	1.75	1.9		3.2	3.8		.,	
VOH	High-level output voltage	$V_{ID} = 100 \text{ mV},$ $I_{OH} = -1 \text{ mA}$	Full range	1.7			3			V	
VOL	Low-level output voltage	V _{IC} = 1 V, V _{ID} = - 100 mV,	25°C		115	150		95	150	mV	
VOL	Low-level output voltage	$I_{OL} = 1 \text{ mA}$	Full range			190			190	IIIV	
Δ	Large-signal differential voltage	$V_{IC} = 1 V$, $R_{I} = 1 M\Omega$,	25°C	50	400		50	520		V/mV	
AVD	amplification	See Note 6	Full range	50			50			V/IIIV	
CMDD		V _O = 1 V,	25°C	65	88		65	94		40	
CIVIKK		$V_{IC} = V_{ICR} min,$ $R_S = 50 \Omega$	Full range	60			60			dB	
leaves	ksvr Supply-voltage rejection ratio $V_{IC} = 1 \text{ V}, V_{O} = 1 \text{ V}, V_{O} = 1 \text{ V}, R_{S} = 50 \Omega$		25°C	70	86		70	86		٩D	
rsvr			Full range	65			65			dB	
Inn	Supply current	$V_{O} = 1 \text{ V}, V_{IC} = 1 \text{ V},$	25°C		12	34		20	34	μА	
IDD	Supply current	No load	Full range			54			54	μΑ	

†Full range is -40°C to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.

6. At V_{DD} = 5 V, $V_{O(PP)}$ = 0.25 V to 2 V; at V_{DD} = 3 V, V_{O} = 0.5 V to 1.5

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TLV2322 operating characteristics at specified free-air temperature, $V_{DD} = 3 \text{ V}$

	PARAMETER	TEST CO	ONDITIONS	т.	Т	LV2322		UNIT
	PARAMETER	1531 CC	SNOTTIONS	TA	MIN	TYP	MAX	UNII
SR	Slew rate at unity gain	$V_{IC} = 1 \text{ V},$ $R_{I} = 1 \text{ M}\Omega,$	V _{I(PP)} = 1 V, C _L = 20 pF,	25°C		0.02		V/µs
J N	Siew rate at unity gain	See Figure 35	OL = 20 pr,	85°C		0.02		ν/μδ
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 36	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
Post	Maximum output-swing bandwidth	Vo = VoH,	C _L = 20 pF,	25°C		2.5		kHz
ВОМ	Maximum output-swing bandwidth	$R_L = 1 M\Omega$,	See Figure 35	85°C		2		KI IZ
B ₁	Unity-gain bandwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		27		kHz
	Only-gain bandwidth	$R_L = 1 M\Omega$, See Figure		85°C		21		KI IZ
		$V_{I} = 10 \text{ mV},$	f= B ₁ ,	-40°C		39°		
φm	Phase margin	$C_L = 20 \text{ pF},$	$R_L = 1 M\Omega$,	25°C		34°		
		See Figure 37		85°C		28°		

TLV2322 operating characteristics at specified free-air temperature, $V_{DD} = 5 \text{ V}$

	DADAMETER	TEST 0.0	NIDITIONS	T.	Т	LV2322		LINIT	
	PARAMETER	IESTCC	ONDITIONS	TA	MIN	TYP	MAX	UNIT	
		V _{IC} = 1 V,	\/\(\max_1 = 1 \/	25°C		0.03			
SR	Slow rate at unity gain	$R_L = 1 M\Omega$,	V _{I(PP)} = 1 V	85°C		0.03		\//uo	
Jok	Slew rate at unity gain	$C_L = 20 \text{ pF},$	V((DD) = 2.5.V	25°C		0.03		V/μs	
		See Figure 35	V _{I(PP)} = 2.5 V	85°C		0.02			
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 36	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz	
Davi	Maximum autout auting handwidth	VO = VOH,	C _L = 20 pF,	25°C		5		kHz	
ВОМ	Maximum output-swing bandwidth	$R_L = 1 M\Omega$,	See Figure 35	85°C		4		KITZ	
Б.	Unity gain bandwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		85		kHz	
B ₁	Unity-gain bandwidth $R_L = 1 M\Omega$,		See Figure 37	85°C		55		KΠZ	
		V _I = 10 mV,	f = B ₁ ,	−40°C		38°			
φm	Phase margin	$C_L = 20 pF$,	$R_L = 1 M\Omega$,	25°C		34°			
		See Figure 37		85°C		28°			

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TLV2324I electrical characteristics at specified free-air temperature

						TLV2	3241			
	PARAMETER	TEST CONDITIONS	T _A †	VI	OD = 3 \	/	V	DD = 5 V	'	UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
VIO	Input offset voltage	$V_{O} = 1 V,$ $V_{IC} = 1 V,$	25°C		1.1	10		1.1	10	mV
۷۱٥	input onset voltage	$R_S = 50 \Omega$, $R_L = 1 M\Omega$,	Full range			12			12	1117
αΝΙΟ	Average temperature coefficient of input offset voltage		25°C to 85°C		1			1.1		μV/°C
lio.	Input offset current (see Note 4)	V _O = 1 V,	25°C		0.1			0.1		pA
10	input onset current (see Note 4)	V _{IC} = 1 V	85°C		22	1000		24	1000	pΑ
I _{IB}	Input bias current (see Note 4)	$V_0 = 1 V$,	25°C		0.6			0.6		pA
,ID		V _{IC} = 1 V	85°C		175	2000		200	2000	P/ \
			0500	-0.2	-0.3		-0.2	-0.3		
	Common-mode input		25°C	to 2	to 2.3		to 4	to 4.2		V
VICR	voltage range (see Note 5)			-0.2			-0.2			
			Full range	, , ,			to			V
				1.8			3.8			
	Lligh lovel output voltage	V _{IC} = 1 V, V _{ID} = 100 mV,	25°C	1.75	1.9		3.2	3.8		V
VOH	High-level output voltage	I _{OH} = -1 mA	Full range	1.7			3			V
.	Lave laved autout value	V _{IC} = 1 V,	25°C		115	150		95	150	> /
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 1 \text{ mA}$	Full range			190			190	mV
	Large-signal differential	V _{IC} = 1 V,	25°C	50	400		50	520		
AVD	voltage amplification	$R_L = 1 MΩ$, See Note 6	Full range	50			50			V/mV
OMBE	0	V _O = 1 V,	25°C	65	88		65	94		10
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR}$ min, RS = 50 Ω	Full range	60			60			dB
keye	Supply-voltage rejection ratio	$V_{IC} = 1 \text{ V}, V_{O} = 1 \text{ V},$	25°C	70	86		70	86		dB
ksvr	(ΔV _{DD} /ΔV _{IO})	$R_S = 50 \Omega$	Full range	65			65			ub_
lDD	Supply current	$V_{O} = 1 \text{ V}, V_{IC} = 1 \text{ V},$	25°C		24	68		39	68	μА
טטי	очерну очители	No load	Full range			108			108	μΛ

[†] Full range is -40° C to 85° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.

- 6. At $V_{DD} = 5 \text{ V}$, $V_{O(PP)} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 3 \text{ V}$, $V_{O} = 0.5 \text{ V}$ to 1.5 V.

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TLV2324I operating characteristics at specified free-air temperature, $V_{DD} = 3 \text{ V}$

	PARAMETER	TEST C	ONDITIONS	т.	Т	V2324I		UNIT
	PARAMETER	IESI CO	SNOTTIONS	T _A	MIN	TYP	MAX	UNIT
SR	Slew rate at unity gain	$V_{IC} = 1 \text{ V},$ $R_{I} = 1 \text{ M}\Omega,$	V _{I(PP)} = 1 V, C _L = 20 pF,	25°C		0.02		V/µs
J SK	Siew rate at unity gain	See Figure 35	CL = 20 pr,	85°C		0.02		ν/μδ
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 36	$R_S = 20 \Omega$,	25°C		68		nV√/Hz
Para	Maximum output-swing bandwidth	$V_O = V_{OH}$	C _L = 20 pF,	25°C		2.5		kHz
ВОМ	Maximum output-swing bandwidth	$R_L = 1 M\Omega$,	See Figure 35	85°C		2		KIIZ
р.	Unity-gain bandwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		27		kHz
B ₁	Offity-gain bandwidth	$R_L = 1 M\Omega$,	See Figure 37	85°C		21		KIIZ
		V _I = 10 mV,	$f = B_1$,	−40°C		39°		
φm	Phase margin	$C_L = 20 pF$,	$R_L = 1 M\Omega$,	25°C		34°		
		See Figure 37		85°C		28°		

TLV2324I operating characteristics at specified free-air temperature, $V_{DD} = 5 \text{ V}$

	DADAMETED	TEOT 04	ANDITIONS.		Т	LV2324I		
	PARAMETER	TEST CO	TA	MIN	TYP	MAX	UNIT	
		V _{IC} = 1 V,	V((pp) = 1)/	25°C		0.03		
SR	Slow rate at unity gain	$R_L = 1 M\Omega$,	V _{I(PP)} = 1 V	85°C		0.03		\////
J SK	Slew rate at unity gain	$C_L = 20 \text{ pF},$	V(100) - 25 V	25°C		0.03		V/μs
		See Figure 35	$V_{I(PP)} = 2.5 V$	85°C		0.02		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 36	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
Davi	Maximum autout aving handvidth	$V_O = V_{OH}$	C _L = 20 pF,	25°C		5		lel I=
ВОМ	Maximum output-swing bandwidth	$R_L = 1 M\Omega$,	See Figure 35	85°C		4		kHz
В.	Linite, and a hondridth	V _I = 10 mV,	C _L = 20 pF,	25°C		85		kHz
B ₁	Unity-gain bandwidth	$R_L = 1 M\Omega$,	See Figure 37	85°C		55		KHZ
		V _I = 10 mV,	f = B ₁ ,	−40°C		38°		
φm	Phase margin	$C_L = 20 \text{ pF},$	$R_L = 1 M\Omega$,	25°C		34°		
		See Figure 37		85°C		28°		

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TLV2322Y electrical characteristics, $T_A = 25^{\circ}C$

						TLV2	322Y			
	PARAMETER	TEST (CONDITIONS	V	DD = 3 \	/	٧ _I	DD = 5 V	1	UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
VIO	Input offset voltage	$V_O = 1 V$, $R_S = 50 \Omega$,	$V_{IC} = 1 V$, $R_L = 1 M\Omega$		1.1			1.1		mV
IIO	Input offset current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.1			0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.6			0.6		pА
VICR	Common-mode input voltage range (see Note 5)				-0.3 to 2.3			-0.3 to 4.2		٧
Vон	High-level output voltage	$V_{IC} = 1 V$, $I_{OH} = -1 \text{ mA}$	$V_{ID} = -100 \text{ mV},$		1.9			3.8		V
V _{OL}	Low-level output voltage	V _{IC} = 1 V, I _{OL} = 1 mA	$V_{ID} = 100 \text{ mV},$		115			95		mV
AVD	Large-signal differential voltage amplification	V _{IC} = 1 V, See Note 6	$R_L = 1 M\Omega$,		400			520		V/mV
CMRR	Common-mode rejection ratio	$V_O = 1 V$, $R_S = 50 \Omega$	$V_{IC} = V_{ICR} min,$		88			94		dB
ksvr	Supply-voltage rejection ratio $(\Delta V_{DD} / \Delta V_{ID})$	$V_O = 1 V$, $R_S = 50 \Omega$	V _{IC} = 1 V,		86			86		dB
I _{DD}	Supply current	V _O = 1 V, No load	V _{IC} = 1 V,		12			20		μΑ

NOTES: 4. The typical values of input bias current offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.

6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 3 \text{ V}$, $V_{O} = 0.5 \text{ V}$ to 1.5 V.

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TLV2322Y electrical characteristics, $T_A = 25^{\circ}C$

				TLV2324Y						UNIT
PARAMETER		TEST CONDITIONS		V _{DD} = 3 V		V _{DD} = 5 V				
				MIN	TYP	MAX	MIN	TYP	MAX	
VIO	Input offset voltage	$V_O = 1 V$, $R_S = 50 \Omega$,	$V_{IC} = 1 V$, $R_L = 1 M\Omega$		1.1			1.1		mV
IIO	Input offset current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.1			0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.6			0.6		pА
VICR	Common-mode input voltage range (see Note 5)				-0.3 to 2.3			-0.3 to 4.2		V
Vон	High-level output voltage	$V_{IC} = 1 V$, $I_{OH} = -1 \text{ mA}$	$V_{ID} = 100 \text{ mV},$	1.9		3.8		V		
VOL	Low-level output voltage	V _{IC} = 1 V, I _{OL} = 1 mA	$V_{ID} = 100 \text{ mV},$	115		95		mV		
A _{VD}	Large-signal differential voltage amplification	V _{IC} = 1 V, See Note 6	$R_L = 1 M\Omega$,	400		520		V/mV		
CMRR	Common-mode rejection ratio	$V_O = 1 V$, $R_S = 50 \Omega$	$V_{IC} = V_{ICR}min,$	88			94		dB	
ksvr	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{ID})$	$V_O = 1 V$, $R_S = 50 \Omega$	V _{IC} = 1 V,	86			86		dB	
I _{DD}	Supply current	V _O = 1 V, No load	V _{IC} = 1 V,	24			39		μΑ	

NOTES: 4. The typical values of input bias current offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.

6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 3 \text{ V}$, $V_{O} = 0.5 \text{ V}$ to 1.5 V.

TLV2322, TLV2322Y, TLV2324, TLV2324Y LinCMOS™ LOW-VOLTAGE LOW-POWER OPERATIONAL AMPLIFIERS SLOS187 – FEBRUARY 1997

TYPICAL CHARACTERISTICS

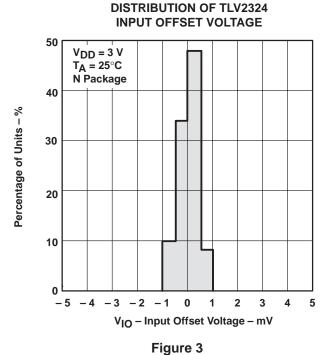
Table of Graphs

			FIGURE
VIO	Input offset voltage	Distribution	1 – 4
ανιο	Input offset voltage temperature coefficient	Distribution	5 – 8
I _{IB}	Input bias current	vs Free-air temperature	9
lιο	Input offset current	vs Free-air temperature	9
VIC	Common-mode input voltage	vs Supply voltage	10
VOH	High-level output voltage	vs High-level output current vs Supply voltage vs Free-air temperature	11 12 13
VOL	Low-level output voltage	vs Common-mode input voltage vs Free-air temperature vs Differential input voltage vs Low-level output current	14 15, 16 17 18
AVD	Large-signal differential voltage amplification	vs Supply voltage vs Free-air temperature vs Frequency	19 20 21, 22
I _{DD}	Supply current	vs Supply voltage vs Free-air temperature	23 24, 25
SR	Slew rate	vs Supply voltage vs Free-air temperature	26 27
VO(PP)	Maximum peak-to-peak output voltage	vs Frequency	28
B ₁	Unity-gain bandwidth	vs Supply voltage vs Free-air temperature	29 30
фm	Phase margin	vs Supply voltage vs Free-air temperature vs Load capacitance	31 32 33
	Phase shift	vs Frequency	21, 22
Vn	Equivalent input noise voltage	vs Frequency	34

TYPICAL CHARACTERISTICS

DISTRIBUTION OF TLV2322 INPUT OFFSET VOLTAGE 50 VDD = 3 V TA = 25°C P Package 20 10 -5 -4 -3 -2 -1 0 1 2 3 4 5 VIO – Input Offset Voltage – mV

Figure 1



DISTRIBUTION OF TLV2322 INPUT OFFSET VOLTAGE

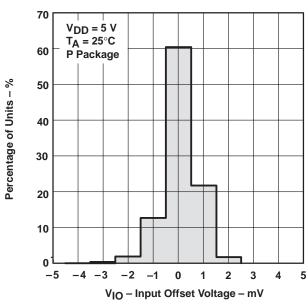


Figure 2

DISTRIBUTION OF TLV2324

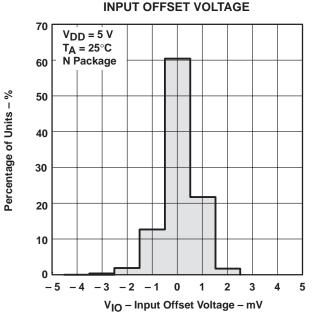
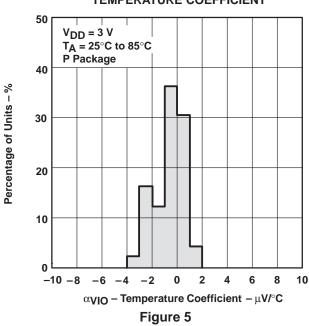


Figure 4

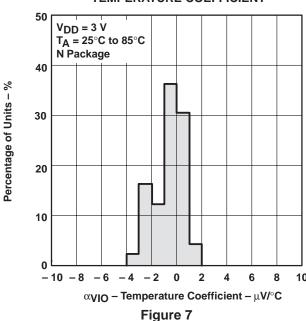
TYPICAL CHARACTERISTICS

Percentage of Units – %

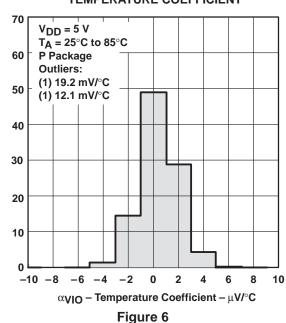
DISTRIBUTION OF TLV2322 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



DISTRIBUTION OF TLV2324 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



DISTRIBUTION OF TLV2322 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



DISTRIBUTION OF TLV2324 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT

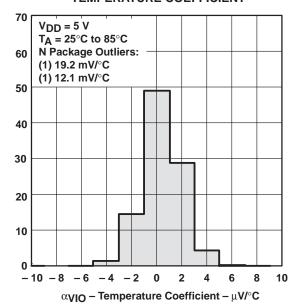


Figure 8

Percentage of Units – %

TYPICAL CHARACTERISTICS

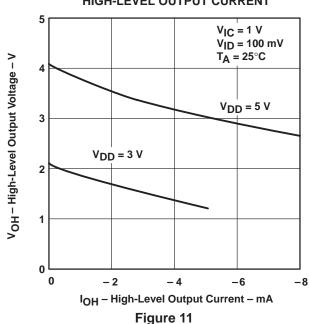
INPUT BIAS CURRENT AND INPUT OFFSET CURRENT

FREE-AIR TEMPERATURE 104 IIB and IIO - Input Bias and Offset Currents - pA $V_{DD} = 3 V$ V_{IC} = 1 V See Note A 103 10² lιΒ 101 lιο 1 0.1 45 25 65 85 105 125 T_A - Free-Air Temperature - °C

NOTE A: The typical values of input bias current and input offset current below 5 pA were determined mathematically.

Figure 9

HIGH-LEVEL OUTPUT VOLTAGE vs HIGH-LEVEL OUTPUT CURRENT



COMMON-MODE INPUT VOLTAGE

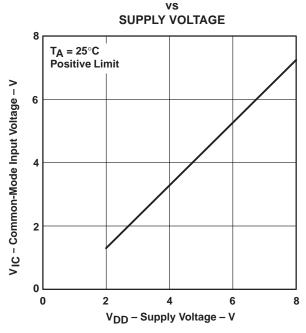
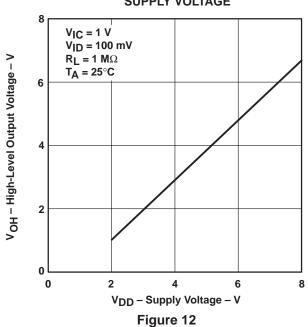


Figure 10

HIGH-LEVEL OUTPUT VOLTAGE vs SUPPLY VOLTAGE



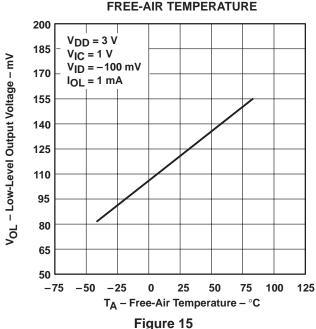
TYPICAL CHARACTERISTICS

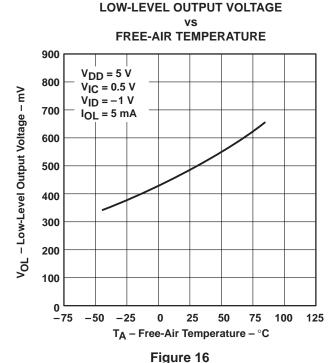
HIGH-LEVEL OUTPUT VOLTAGE FREE-AIR TEMPERATURE $V_{DD} = 3 V$ $V_{IC} = 1 V$ VOH - High-Level Output Voltage - V $V_{ID} = 100 \text{ mV}$ 2.4 1.8 1.2 $I_{OH} = -500 \, \mu A$ IOH = -1 mA IOH = -2 mA0.6 $I_{OH} = -3 \text{ mA}$ $I_{OH} = -4 \text{ mA}$ -75 -50 -25 25 50 75 100 125 T_A – Free-Air Temperature – $^{\circ}$ C Figure 13

COMMON-MODE INPUT VOLTAGE 700 $V_{DD} = 5 V$ $I_{OL} = 5 \text{ mA}$ 650 $T_A = 25^{\circ}C$ Low-Level Output Voltage – mV 600 550 $V_{ID} = -100 \text{ mV}$ 500 450 400 $V_{ID} = -1 V$ 350 300 1.5 2 2.5 0 3.5 V_{IC} - Common-Mode Input Voltage - V Figure 14

LOW-LEVEL OUTPUT VOLTAGE

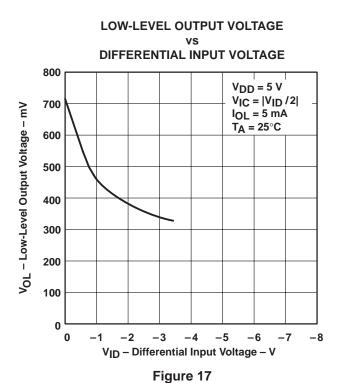
LOW-LEVEL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE



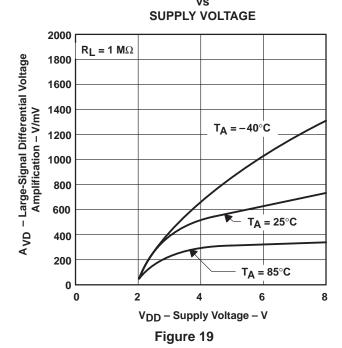


i igaic io

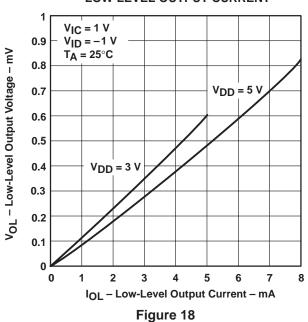
TYPICAL CHARACTERISTICS



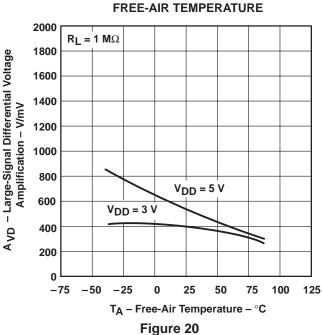
LARGE-SIGNAL
DIFFERENTIAL VOLTAGE AMPLIFICATION



LOW-LEVEL OUTPUT VOLTAGE
vs
LOW-LEVEL OUTPUT CURRENT



LARGE-SIGNAL
DIFFERENTIAL VOLTAGE AMPLIFICATION
vs





TYPICAL CHARACTERISTICS

LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

FREQUENCY 107 **- 60**° $V_{DD} = 3 V$ $R_L = 1 M\Omega$ 106 **- 30**° $C_L = 20 pF$ $T_A = 25^{\circ}C$ 10⁵ AVD - Large-Signal Differential **0**° Voltage Amplification 104 Phase Shift 30° A_{VD} 10³ 60° 10² 90° **Phase Shift** 101 120° 1 150° 180° 0.1 10 100 1 k 10 k 100 k 1 M f - Frequency - Hz

Figure 21

LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

FREQUENCY 107 **–** 60° $V_{DD} = 5 V$ $R_L = 1 M\Omega$ 106 - 30° $C_{L}^{-} = 20 \text{ pF}$ $T_A = 25^{\circ}C$ 10⁵ AVD - Large-Signal Differential **0**° Voltage Amplification 104 30° Phase Shift AVD 103 60° 102 90° Phase Shift 101 120° 150° 1 0.1 180° 10 10 k 100 k 1 M 100 1 k f - Frequency - Hz

Figure 22



TYPICAL CHARACTERISTICS

IDD - Supply Current - μA

-75

-50

-25

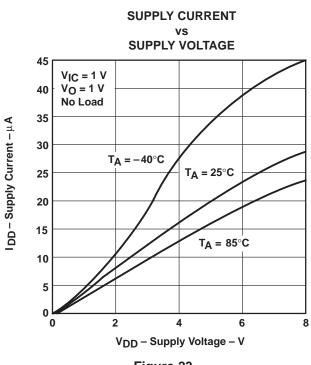
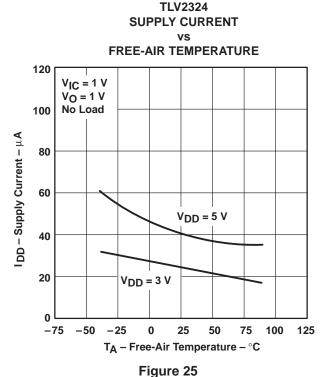


Figure 23



SUPPLY CURRENT
VS
FREE-AIR TEMPERATURE

35
30
VIC = 1 V
VO = 1 V
No Load
25
VDD = 5 V

20
15
10
VDD = 3 V

Figure 24

25

T_A - Free-Air Temperature - °C

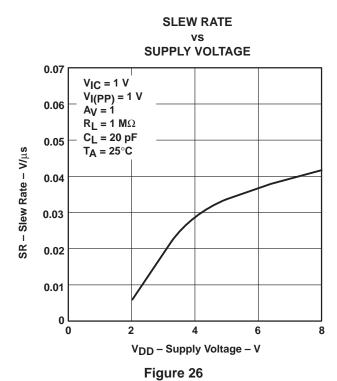
50

75

100

125

0





TYPICAL CHARACTERISTICS

VO(PP) - Maximum Peak-to-Peak Output Voltage - V

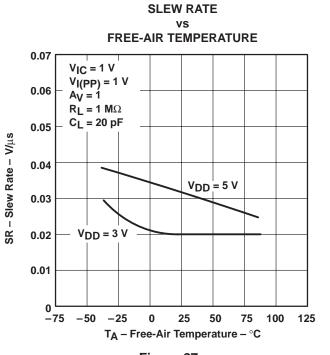
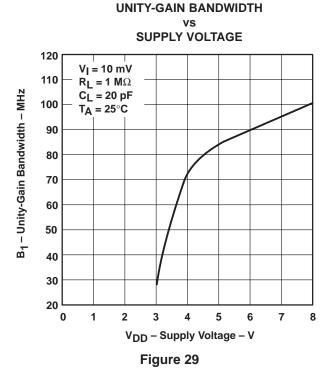


Figure 27



MAXIMUM PEAK-TO-PEAK OUTPUT VOLTAGE vs FREQUENCY

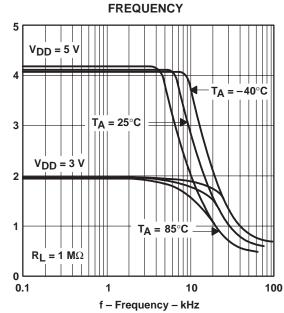


Figure 28

UNITY-GAIN BANDWIDTH vs

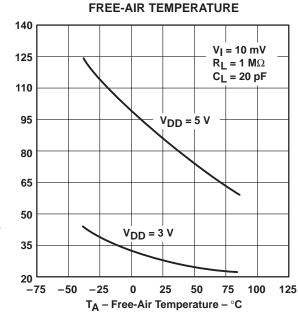


Figure 30

- Unity-Gain Bandwidth - kHz

PHASE MARGIN

SLOS187 - FEBRUARY 1997

TYPICAL CHARACTERISTICS

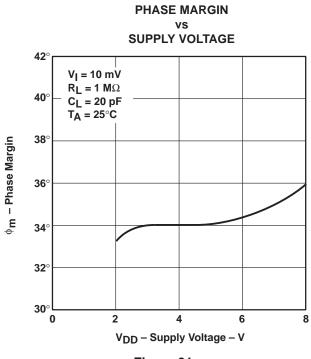


Figure 31

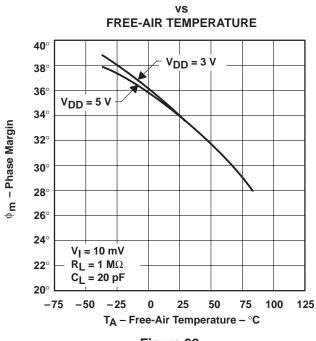
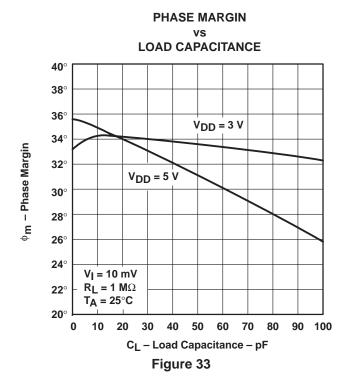
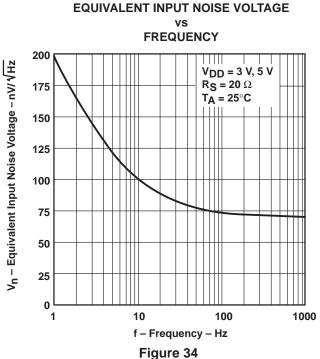


Figure 32





TEXAS

PARAMETER MEASUREMENT INFORMATION

single-supply versus split-supply test circuits

Because the TLV232x is optimized for single-supply operation, circuit configurations used for the various tests often present some inconvenience since the input signal, in many cases, must be offset from ground. This inconvenience can be avoided by testing the device with split supplies and the output load tied to the negative rail. A comparison of single-supply versus split-supply test circuits is shown below. The use of either circuit gives the same result.

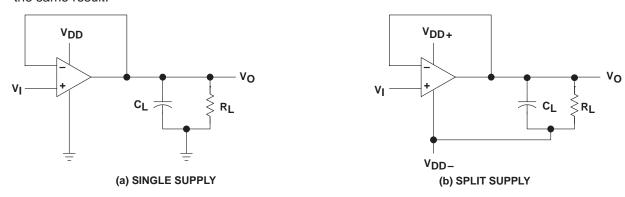


Figure 35. Unity-Gain Amplifier

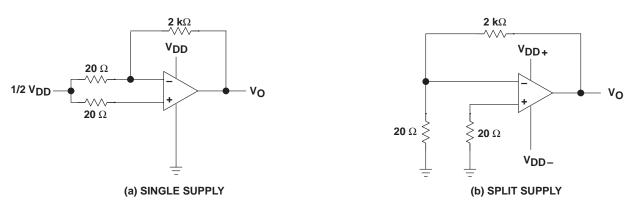


Figure 36. Noise-Test Circuits

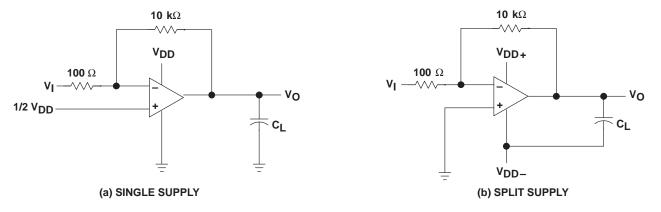


Figure 37. Gain-of-100 Inverting Amplifier



PARAMETER MEASUREMENT INFORMATION

input bias current

Because of the high input impedance of the TLV232x operational amplifier, attempts to measure the input bias current can result in erroneous readings. The bias current at normal ambient temperature is typically less than 1 pA, a value that is easily exceeded by leakages on the test socket. Two suggestions are offered to avoid erroneous measurements:

- Isolate the device from other potential leakage sources. Use a grounded shield around and between the device inputs (see Figure 38). Leakages that would otherwise flow to the inputs are shunted away.
- Compensate for the leakage of the test socket by actually performing an input bias current test (using a
 picoammeter) with no device in the test socket. The actual input bias current can then be calculated by
 subtracting the open-socket leakage readings from the readings obtained with a device in the test
 socket.

Many automatic testers as well as some bench-top operational amplifier testers use the servo-loop technique with a resistor in series with the device input to measure the input bias current (the voltage drop across the series resistor is measured and the bias current is calculated). This method requires that a device be inserted into a test socket to obtain a correct reading; therefore, an open-socket reading is not feasible using this method.

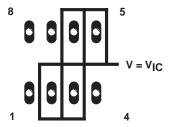


Figure 38. Isolation Metal Around Device Inputs (P package)

low-level output voltage

To obtain low-level supply-voltage operation, some compromise is necessary in the input stage. This compromise results in the device low-level output voltage being dependent on both the common-mode input voltage level as well as the differential input voltage level. When attempting to correlate low-level output readings with those quoted in the electrical specifications, these two conditions should be observed. If conditions other than these are to be used, please refer to the Typical Characteristics section of this data sheet.

input offset voltage temperature coefficient

Erroneous readings often result from attempts to measure the temperature coefficient of input offset voltage. This parameter is actually a calculation using input offset voltage measurements obtained at two different temperatures. When one (or both) of the temperatures is below freezing, moisture can collect on both the device and the test socket. This moisture results in leakage and contact resistance that can cause erroneous input offset voltage readings. The isolation techniques previously mentioned have no effect on the leakage since the moisture also covers the isolation metal itself, thereby rendering it useless. These measurements should be performed at temperatures above freezing to minimize error.

full-power response

Full-power response, the frequency above which the operational amplifier slew rate limits the output voltage swing, is often specified two ways: full-linear response and full-peak response. The full-linear response is



PARAMETER MEASUREMENT INFORMATION

generally measured by monitoring the distortion level of the output while increasing the frequency of a sinusoidal input signal until the maximum frequency is found above which the output contains significant distortion. The full-peak response is defined as the maximum output frequency, without regard to distortion, above which full peak-to-peak output swing cannot be maintained.

Because there is no industry-wide accepted value for significant distortion, the full-peak response is specified in this data sheet and is measured using the circuit of Figure 35. The initial setup involves the use of a sinusoidal input to determine the maximum peak-to-peak output of the device (the amplitude of the sinusoidal wave is increased until clipping occurs). The sinusoidal wave is then replaced with a square wave of the same amplitude. The frequency is then increased until the maximum peak-to-peak output can no longer be maintained (Figure 39). A square wave is used to allow a more accurate determination of the point at which the maximum peak-to-peak output is reached.

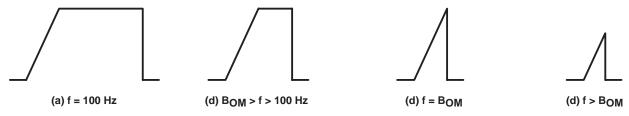


Figure 39. Full-Power-Response Output Signal

test time

Inadequate test time is a frequent problem, especially when testing CMOS devices in a high-volume, short-test-time environment. Internal capacitances are inherently higher in CMOS than in bipolar and BiFET devices and require longer test times than their bipolar and BiFET counterparts. The problem becomes more pronounced with reduced supply levels and lower temperatures.

APPLICATION INFORMATION

single-supply operation

While the TLV232x performs well using dual-power supplies (also called balanced or split supplies), the design is optimized for single-supply operation. This includes an input common-mode voltage range that encompasses ground as well as an output voltage range that pulls down to ground. The supply voltage range extends down to 2 V, thus allowing operation with supply levels commonly available for TTL and HCMOS.

Many single-supply applications require that a voltage be applied to one input to establish a reference level that is above ground. This virtual ground can be generated using two large resistors, but a preferred technique is to use a

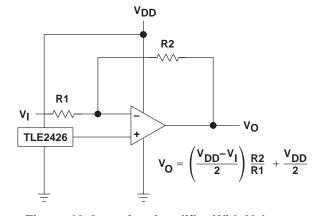


Figure 40. Inverting Amplifier With Voltage Reference

virtual-ground generator such as the TLE2426 (see Figure 40). The TLE2426 supplies an accurate voltage equal to $V_{DD}/2$, while consuming very little power and is suitable for supply voltages of greater than 4 V.

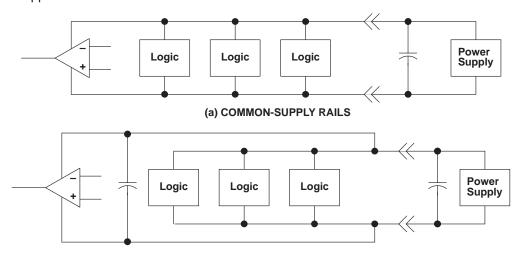


APPLICATION INFORMATION

single-supply operation (continued)

The TLV232x works well in conjunction with digital logic; however, when powering both linear devices and digital logic from the same power supply, the following precautions are recommended:

- Power the linear devices from separate bypassed supply lines (see Figure 41); otherwise, the linear device supply rails can fluctuate due to voltage drops caused by high switching currents in the digital logic.
- Use proper bypass techniques to reduce the probability of noise-induced errors. Single capacitive
 decoupling is often adequate; however, RC decoupling may be necessary in high-frequency
 applications.



(b) SEPARATE-BYPASSED SUPPLY RAILS (preferred)

Figure 41. Common Versus Separate Supply Rails

input characteristics

The TLV232x is specified with a minimum and a maximum input voltage that, if exceeded at either input, could cause the device to malfunction. Exceeding this specified range is a common problem, especially in single-supply operation. The lower the range limit includes the negative rail, while the upper range limit is specified at $V_{DD} - 1 \text{ V}$ at $T_A = 25^{\circ}\text{C}$ and at $V_{DD} - 1.2 \text{ V}$ at all other temperatures.

The use of the polysilicon-gate process and the careful input circuit design gives the TLV232x very good input offset voltage drift characteristics relative to conventional metal-gate processes. Offset voltage drift in CMOS devices is highly influenced by threshold voltage shifts caused by polarization of the phosphorus dopant implanted in the oxide. Placing the phosphorus dopant in a conductor (such as a polysilicon gate) alleviates the polarization problem, thus reducing threshold voltage shifts by more than an order of magnitude. The offset voltage drift with time has been calculated to be typically $0.1~\mu\text{V/month}$, including the first month of operation.

Because of the extremely high input impedance and resulting low bias-current requirements, the TLV232x is well suited for low-level signal processing; however, leakage currents on printed-circuit boards and sockets can easily exceed bias-current requirements and cause a degradation in device performance. It is good practice to include guard rings around inputs (similar to those of Figure 38 in the Parameter Measurement Information section). These guards should be driven from a low-impedance source at the same voltage level as the common-mode input (see Figure 42).

The inputs of any unused amplifiers should be tied to ground to avoid possible oscillation.



APPLICATION INFORMATION

input characteristics (continued)

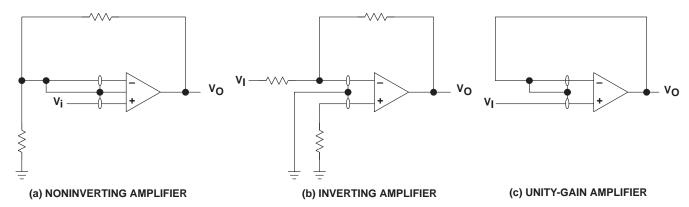


Figure 42. Guard-Ring Schemes

noise performance

The noise specifications in operational amplifier circuits are greatly dependent on the current in the first-stage differential amplifier. The low input bias-current requirements of the TLV232x result in a very low noise current, which is insignificant in most applications. This feature makes the device especially favorable over bipolar devices when using values of circuit impedance greater than 50 k Ω , since bipolar devices exhibit greater noise currents.

feedback

Operational amplifier circuits nearly always employ feedback, and since feedback is the first prerequisite for oscillation, caution is appropriate. Most oscillation problems result from driving capacitive loads and ignoring stray input capacitance. A small-value capacitor connected in parallel with the feedback resistor is an effective remedy (see Figure 43). The value of this capacitor is optimized empirically.

*

internal Figure 43. Compensation for Input Capacitance

electrostatic-discharge protection

The TLV232x incorporates an internal electrostatic-discharge (ESD)-protection circuit

that prevents functional failures at voltages up to 2000 V as tested under MIL-PRF-38535, Method 3015.2. Care should be exercised, however, when handling these devices as exposure to ESD can result in the degradation of the device parametric performance. The protection circuit also causes the input bias currents to be temperature dependent and have the characteristics of a reverse-biased diode.

latch-up

Because CMOS devices are susceptible to latch-up due to their inherent parasitic thyristors, the TLV232x inputs and outputs are designed to withstand –100-mA surge currents without sustaining latch-up; however, techniques should be used to reduce the chance of latch-up whenever possible. Internal-protection diodes should not by design be forward biased. Applied input and output voltage should not exceed the supply voltage



APPLICATION INFORMATION

by more than 300 mV. Care should be exercised when using capacitive coupling on pulse generators. Supply transients should be shunted by the use of decoupling capacitors (0.1 μ F typical) located across the supply rails as close to the device as possible.

The current path established if latch-up occurs is usually between the positive supply rail and ground and can be triggered by surges on the supply lines and/or voltages on either the output or inputs that exceed the supply voltage. Once latch-up occurs, the current flow is limited only by the impedance of the power supply and the forward resistance of the parasitic thyristor and usually results in the destruction of the device. The chance of latch-up occurring increases with increasing temperature and supply voltages.

output characteristics

The output stage of the TLV232x is designed to sink and source relatively high amounts of current (see Typical Characteristics). If the output is subjected to a short-circuit condition, this high-current capability can cause device damage under certain conditions. Output current capability increases with supply voltage.

Although the TLV232x possesses excellent high-level output voltage and current capability, methods are available for boosting this capability, if needed. The simplest method involves the use of a pullup resistor (Rp) connected from the output to the positive supply rail (see Figure 44). There are two disadvantages to the use of this circuit. First, the NMOS pulldown transistor N4 (see equivalent schematic) must sink a comparatively large amount of current. In this circuit, N4 behaves like a linear resistor with an on resistance between approximately 60Ω and 180Ω depending on how hard the operational amplifier input is driven. With very low values of Rp, a voltage offset from 0 V at the output occurs. Secondly, pullup resistor Rp acts as a drain load to N4 and the gain of the operational amplifier is reduced at output voltage levels where N5 is not supplying the output current.

All operating characteristics of the TLV232x are measured using a 20-pF load. The device drives

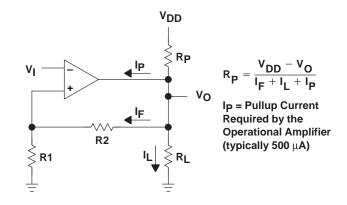


Figure 44. Resistive Pullup to Increase VOH

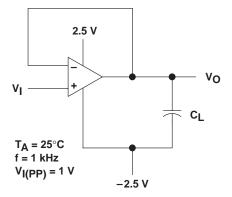


Figure 45. Test Circuit for Output Characteristics

higher capacitive loads; however, as output load capacitance increases, the resulting response pole occurs at lower frequencies, thereby causing ringing, peaking, or even oscillation (see Figure 45 and Figure 46). In many cases, adding some compensation in the form of a series resistor in the feedback loop alleviates the problem.



APPLICATION INFORMATION

output characteristics (continued)

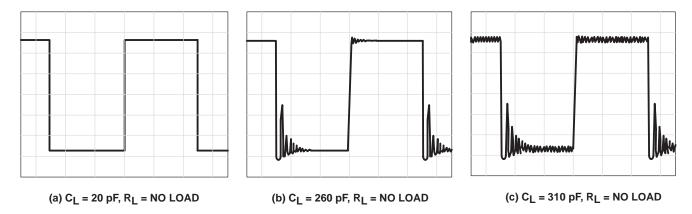


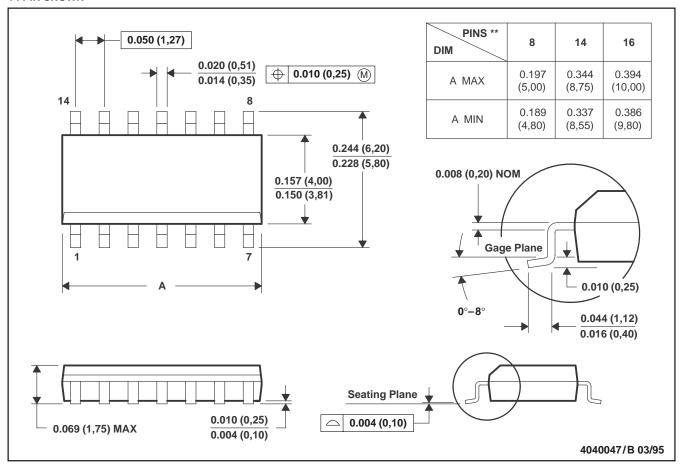
Figure 46. Effect of Capacitive Loads

MECHANICAL INFORMATION

D (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

14 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
- D. Four center pins are connected to die mount pad.
- E. Falls within JEDEC MS-012

TLV2322, TLV2322Y, TLV2324Y LinCMOS™ LOW-VOLTAGE LOW-POWER OPERATIONAL AMPLIFIERS

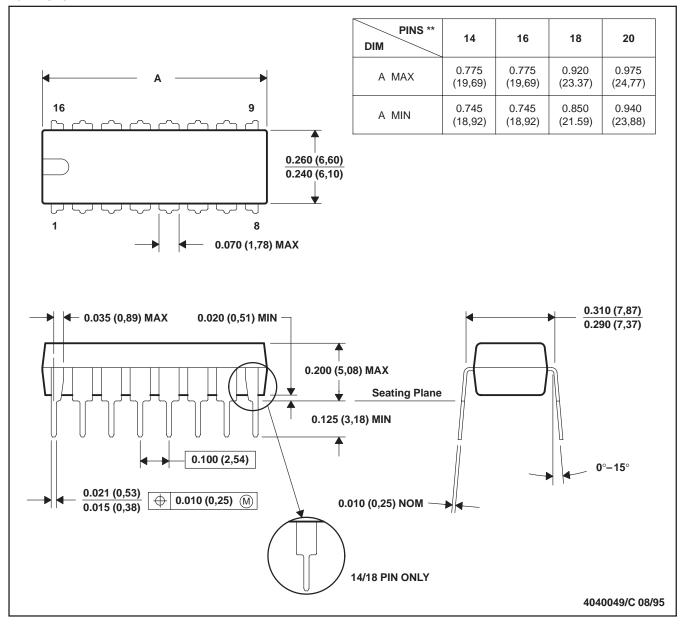
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MECHANICAL INFORMATION

N (R-PDIP-T**)

16 PIN SHOWN

PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

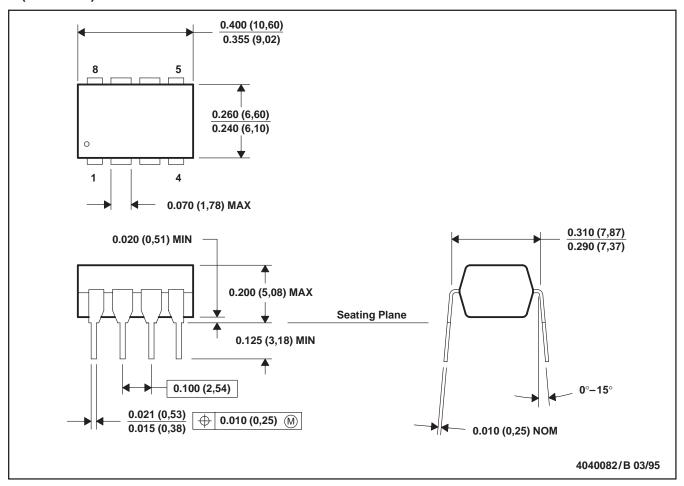
C. Falls within JEDEC MS-001 (20 pin package is shorter then MS-001.)



MECHANICAL INFORMATION

P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001

TLV2322, TLV2322Y, TLV2324, TLV2324Y LinCMOS™ LOW-VOLTAGE LOW-POWER OPERATIONAL AMPLIFIERS

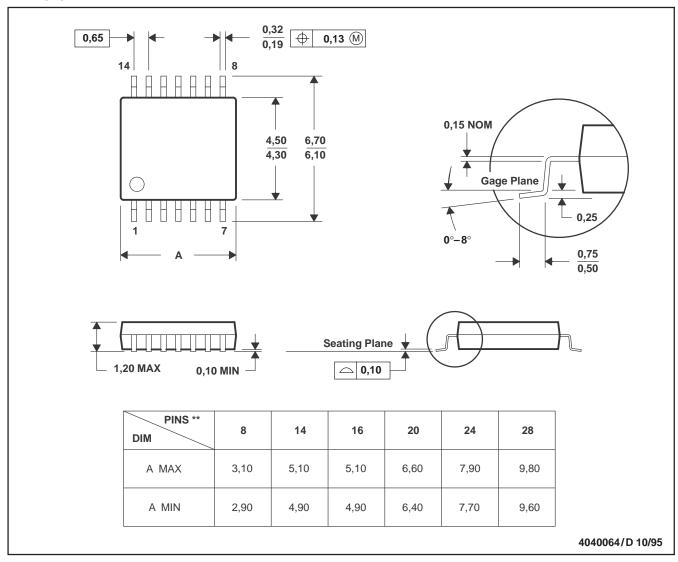
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MECHANICAL INFORMATION

PW (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

14 PIN SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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